	Form PTO 1449 (Modified)			OF COMMERCE DEMARK OFFICE	ATTY DOCKET NO.		SERIAL NO.			
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	EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE		
	MIN	AA	4,511,610	04/1985	YAZAKI et al					
		AB	6,033,749	3/2000	Hata et al	428	36.7			
i		AC	2,830,721	4/1958	Pinsky et al	215	12.2			
		AD	6,467,643	10/2002	Sadr	220	562			
		AE	3,779,420	12/1978	Knaus	220	4.14			
		AF	4,079,850	3/1978	Suzuki et al	215	12.2			
		AG	5,547,096	8/1996	Kleyn	220	4.14			
I		АН	2001/0045433	11/2001	Ellis	220	562			
Ì		Al	5,441,781	8/1995	Uchida et al	428	35.7			
ı	RCM	AJ	5,849,376	12/1998	Oishi et al	428	34.9			
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)										
	Red	AW Derwent Abstract, JP 58-220738, December 22, 1983								
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Form PTO 1449		U.S. DEPARTMENT OF	COMMERCE	ATTY DOCKET NO.	SERIAL NO.				
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MI	イ	AA	6,398,059	06-04-02	HAYASHI et al.					
,	1	AB	6,667/,083	12-23-03	HAYASHI et al.					
la l		AC	6,395,358	05-28-02	TAI et al.					
		AD	6,720,053	04-13-04	TAI et al.					
		AE	6,677,017	01-13-04	TAI et al.	1				
		AF	6,372,359	04-16-02	HAYASHI et al.	<del> </del>		_		
		AG	6,503,588	01-07-03	HAYASHI et al.					
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conformance and not considered. Include copy of this form with next communication to applicant.										